

Reveo-0130USAAON00
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REMARKS

Applicants wish to thank the Examiner for the attention accorded to the instant application.

Claims 1-14 and 32 remain pending in the application. Claims 1, 2, 3 and 32 were amended in an amendment submitted June 6, 2005.

It is respectfully submitted that none of the references, alone or in combination, do not teach a system wherein the wherein the index of refraction of the liquid crystal array and the index of refraction of the polymer matrix, n_p , are mismatched at least at a first, a second and a third applied electric field strengths, the first, second and third field strengths of increasing magnitude, further wherein a characteristic wavelength reflection varies between the first and third applied field, and a characteristic reflectance intensity varies between first and second applied field and varies between the second and third applied field.

The Examiner has maintained his rejection of claims 1-4, 7-13 and 32 as being anticipated by Sutherland et al. U.S. Patent No. 5,942,157. However, unlike the claims herein, Sutherland does not teach that **the characteristic wavelength reflection and that the characteristic reflectance intensity vary across at least three applied electric fields.**

Applicants respectfully submit that claims 1-14 and 32 are in condition for allowance. Early notice to that effect is earnestly solicited.

Respectfully submitted,

By


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